

## 100V, 120A N-CHANNEL POWER MOSFET

### GENERAL DESCRIPTION

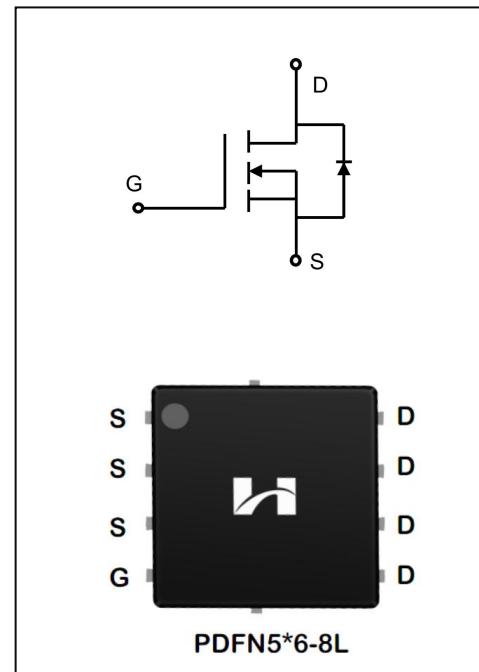
The SGM105R5T uses advanced SGT technology and design to provide excellent  $R_{DS(on)}$  with low gate charge. It can be used in a wide variety applications.

### Features

- ◆  $V_{DS}=100V$ ,  $I_D=120A$
- ◆  $R_{DS(on)}$   
TYP:  $4.6m\Omega$  @  $V_{GS}=10V$   
MAX:  $5.5m\Omega$

### Applications

- ◆ Power factor correction (PFC)
- ◆ Switched mode power supplies (SMPS)
- ◆ Uninterruptible power supply (UPS)
- ◆ LED lighting power



### ORDERING INFORMATION

Part No.	Package	Marking	Material	Packing
SGM105R5T	PDFN5*6-8L	SGM105R5T	Pb Free	Reel

**ABSOLUTE MAXIMUM RATINGS (T<sub>J</sub>=25°C unless otherwise noted)**

Characteristics	Symbol	Ratings	Unit
Drain-Source Voltage	V <sub>DS</sub>	100	V
Gate-Source Voltage	V <sub>GS</sub>	±20	V
Drain Current	I <sub>D</sub>	120	A
T <sub>C</sub> = 100°C	I <sub>D</sub>	84	
Drain Current Pulsed(Note 1)	I <sub>DM</sub>	480	A
Power Dissipation(T <sub>C</sub> =25°C) -Derate above 25°C	P <sub>D</sub>	200	W
Single Pulsed Avalanche Energy (Note 2)	E <sub>AS</sub>	345	mJ
Operation Junction Temperature Range	T <sub>J</sub>	-55~+150	°C
Storage Temperature Range	T <sub>stg</sub>	-55~+150	°C
Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	TL	260	°C

**THERMAL CHARACTERISTICS**

Characteristics	Symbol	MAX	Unit
Thermal Resistance, Junction-to-Case	R <sub>θJC</sub>	0.63	°C/W
Thermal Resistance, Junction-to-Ambient	R <sub>θJA</sub>	62.5	°C/W

**ELECTRICAL CHARACTERISTICS**

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
<b>Off Characteristics</b>						
Drain -Source Breakdown Voltage	B <sub>VDSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	100	--	--	V
Drain-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> =100V, V <sub>GS</sub> =0V	--	--	1	uA
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =20V, V <sub>DS</sub> =0V	--	--	100	nA
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =-20V, V <sub>DS</sub> =0V	--	--	-100	
<b>On Characteristics</b>						
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> =250μA	2.0	3.0	4.0	V
Static Drain- Source On State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =50A	--	4.6	5.5	mΩ
<b>Dynamic Characteristics</b>						
Gate Resistance	R <sub>g</sub>	V <sub>GS</sub> =0V; f=1.0MHZ	--	3.4	--	Ω
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =50V	--	4550	--	pF
Output Capacitance	C <sub>oss</sub>		--	1400	--	
Reverse Transfer Capacitance	C <sub>rss</sub>	f=1.0MHZ	--	1350	--	
<b>Switching Characteristics</b>						
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> =50V, V <sub>DS</sub> =10V R <sub>G</sub> =1.6Ω; I <sub>D</sub> =25A (Note 3.4)	--	20.2	--	ns
Turn-on Rise Time	t <sub>r</sub>		--	38.6	--	
Turn-off Delay Time	t <sub>d(off)</sub>		--	70.1	--	
Turn-off Fall Time	t <sub>f</sub>		--	18.9	--	

Total Gate Charge	$Q_g$	$V_{DS}=50V, I_D=25A$ $V_{GS}=10V$ (Note 3.4)	--	78.1	--	nC
Gate-Source Charge	$Q_{gs}$		--	29.2	--	
Gate-Drain Charge	$Q_{gd}$		--	17.7	--	

## SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	$I_s$	Integral Reverse P-N Junction Diode in the MOSFET	--	--	120	A
Pulsed Source Current	$I_{SM}$		--	--	480	
Diode Forward Voltage	$V_{SD}$	$I_s=50A, V_{GS}=0V$	--	0.87	1.4	V
Reverse Recovery Time	$T_{rr}$	$I_s=50A, V_{GS}=0V,$ $dI/dt=100A/\mu s$	--	61	--	ns
Reverse Recovery Charge	$Q_{rr}$		--	120	--	nC

1. Pulse width limited by maximum junction temperature

2. L=0.1mH,  $V_{DD}=50V$ ,  $V_G=10V$ ,  $R_G=25\Omega$ , starting  $T_J=25^\circ$ 3. Pulse Test: Pulse width  $\leq 300\mu s$ , Duty cycle  $\leq 2\%$ 

4. Essentially independent of operating temperature

## Typical Performance Characteristics

Figure 1. On-Region Characteristics

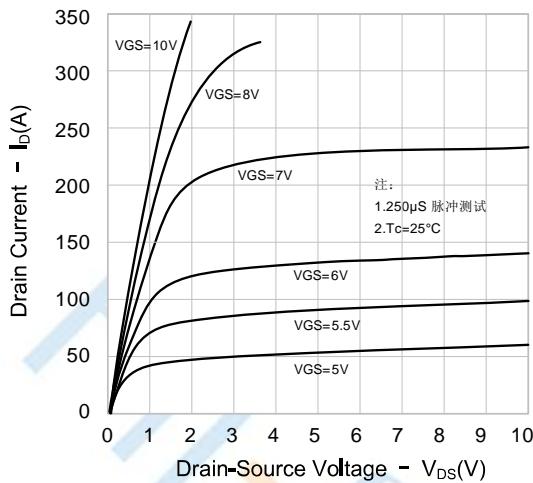


Figure 3. On-Resistance Variation vs. Drain Current

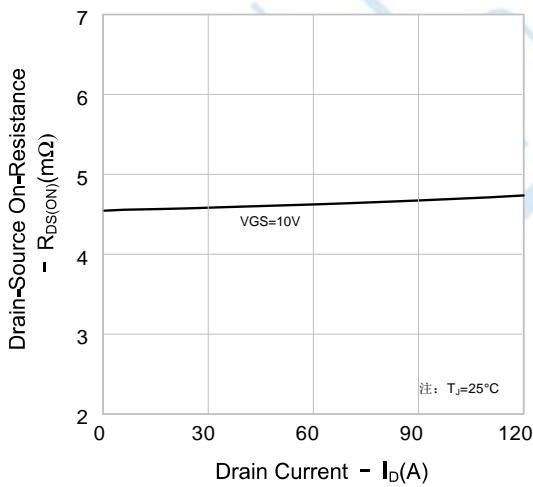


Figure 5. Capacitance Characteristics

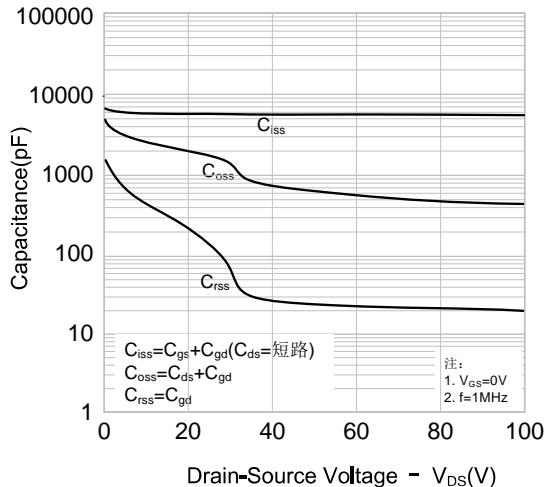


Figure 2. Transfer Characteristics

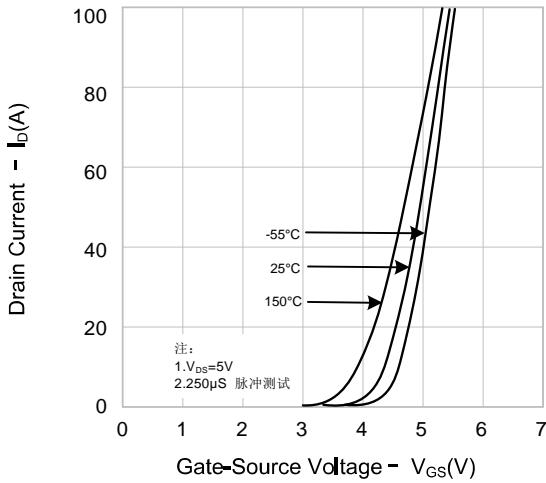


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

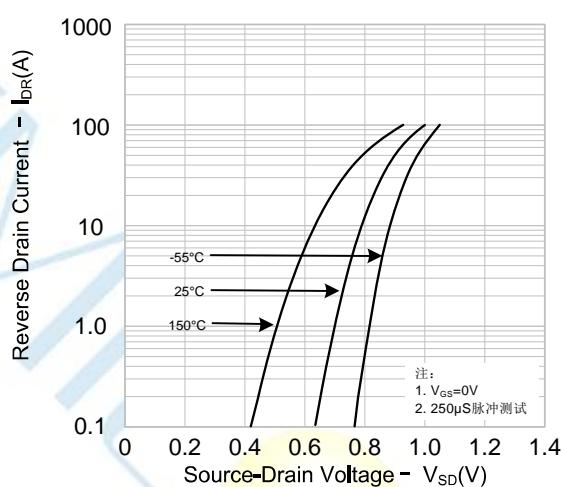
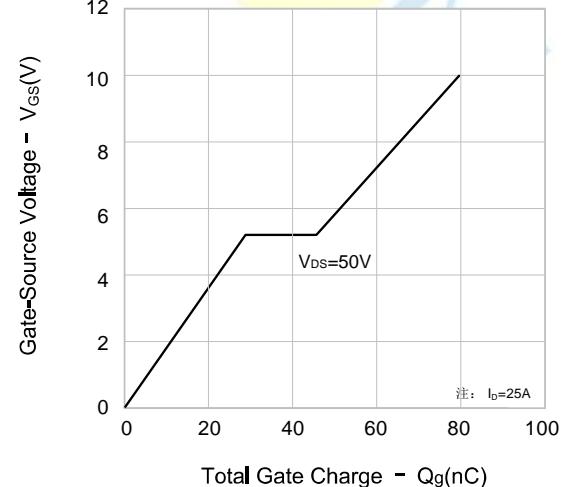


Figure 6. Gate Charge Characteristics



## Typical Performance Characteristics

Figure 7. Breakdown Voltage Variation vs. Temperature

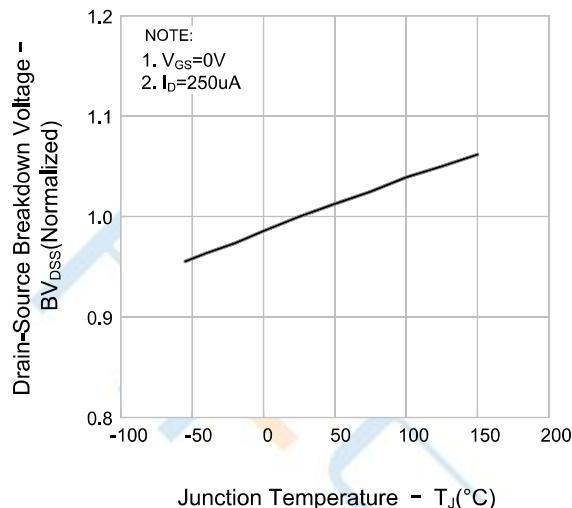


Figure 8. On-resistance Variation vs. Temperature

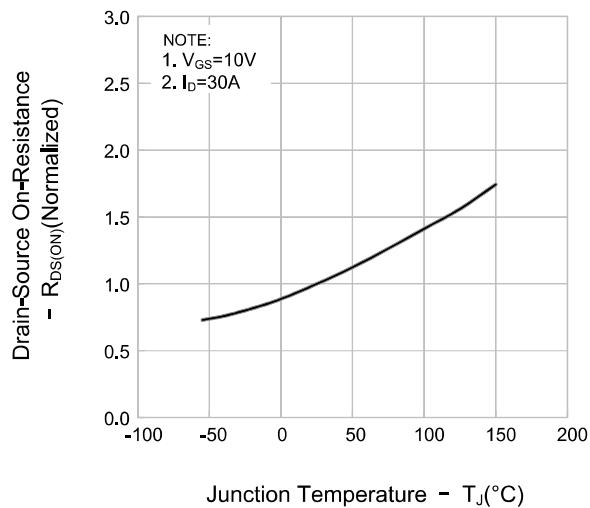
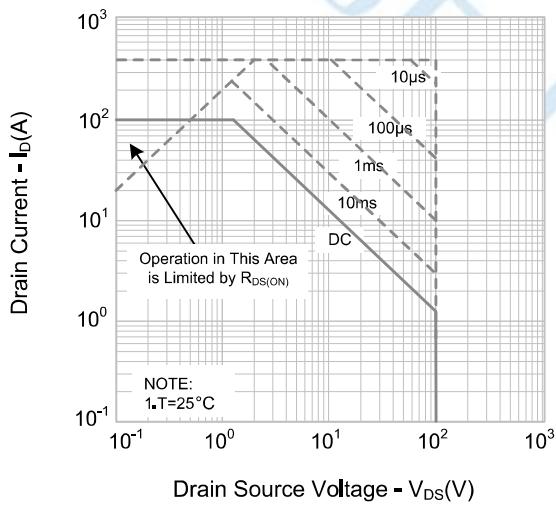
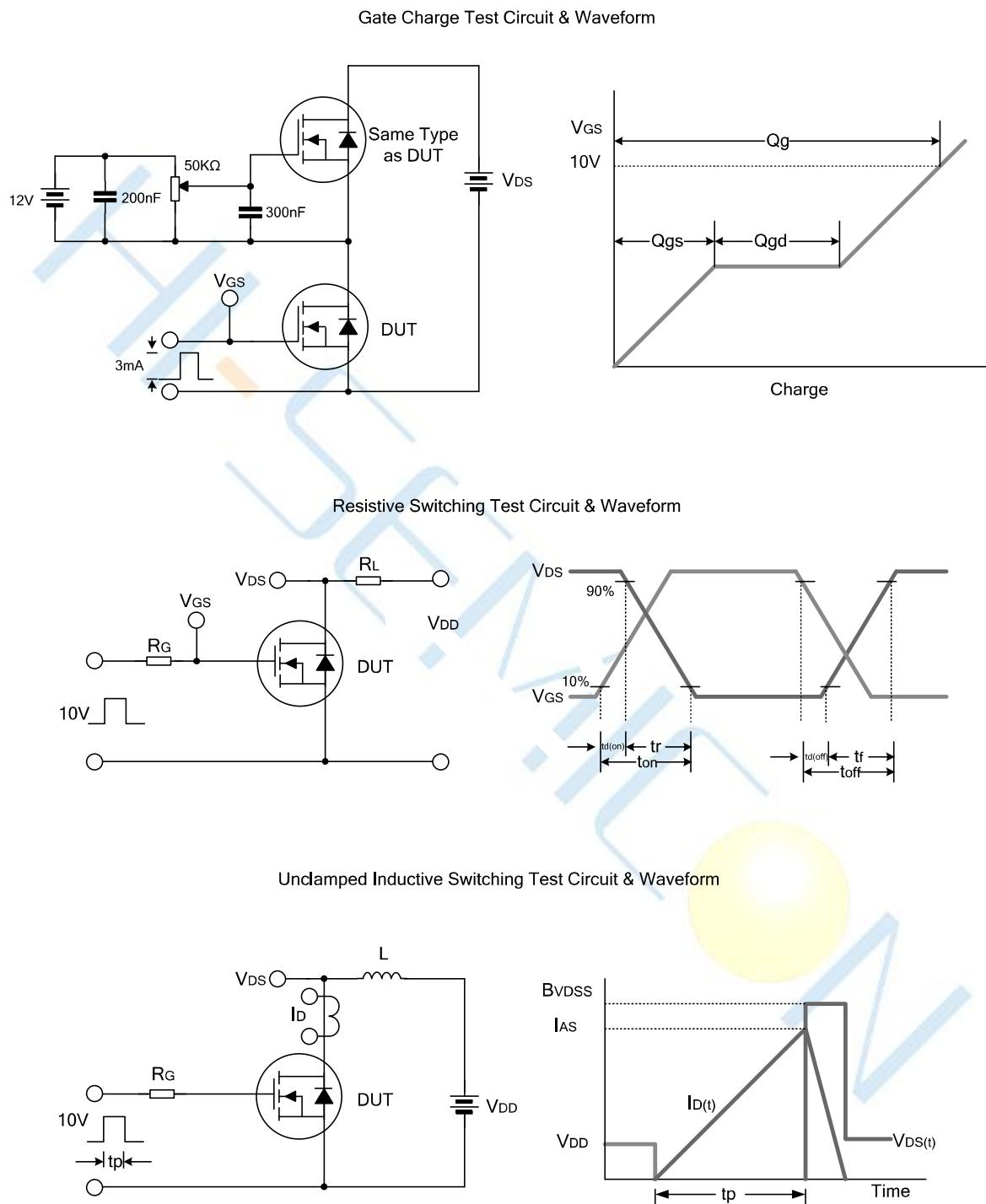


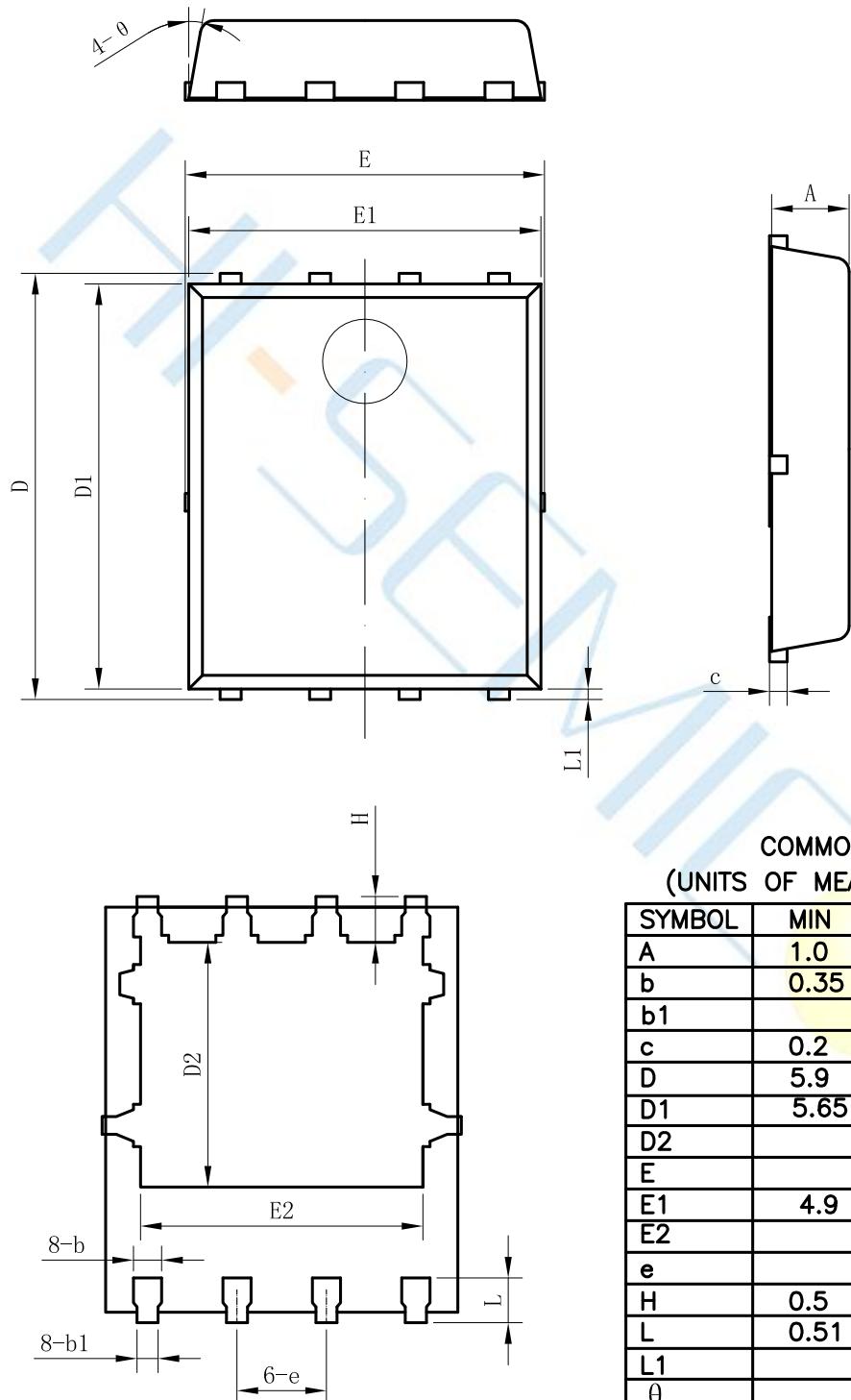
Figure 9. Max Safe Operating Area



**Test Circuit**

## Package Dimensions of PDFN5\*6-8L

Unit:mm



COMMON DIMENSIONS  
(UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	NOM	MAX
A	1.0	1.1	1.2
b	0.35	0.4	0.45
b1		(0.3)	
c	0.2	0.25	0.35
D	5.9	6.05	6.2
D1	5.65	5.75	5.85
D2		(3.475)	
E			5.2
E1	4.9	5	5.1
E2		(4.01)	
e		1.27BSC	
H	0.5	0.65	0.75
L	0.51	0.635	0.75
L1		0.15	
$\theta$		10°	

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